

Mining Compressed Patterns

Pat-ID	Item-Sets	Support
P1	{38,16,18,12}	205227
P2	{38,16,18,12,17}	205211
Р3	{39,38,16,18,12,17}	101758
P4	{39,16,18,12,17}	161563
P5	{39,16,18,12}	161576

- Closed patterns
 - P1, P2, P3, P4, P5
 - Emphasizes too much on support
 - There is no compression
- Max-patterns
 - P3: information loss
- Desired output (a good balance):
 - □ P2, P3, P4

- Why mining compressed patterns?
 - Too many scattered patterns but not so meaningful
- Pattern distance measure

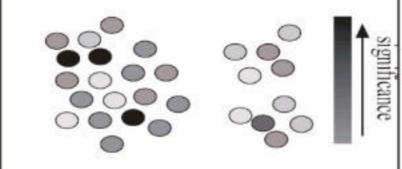
$$Dist(P_1, P_2) = 1 - \frac{|T(P_1) \cap T(P_2)|}{|T(P_1) \cup T(P_2)|}$$

- δ-clustering: For each pattern P, find all patterns which can be expressed by P and whose distance to P is within (δ-cover)
- □ All patterns in the cluster can be represented by P
- Method for efficient, direct mining of compressed frequent patterns (e.g., D. Xin, J. Han, X. Yan, H. Cheng, "On Compressing Frequent Patterns", Knowledge and Data Engineering, 60:5-29, 2007)

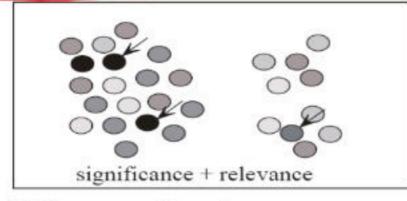
Redundancy-Aware Top-k Patterns

Desired patterns: high significance & low redundancy

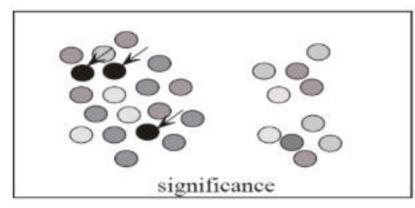
darker: significate lighter: less significat



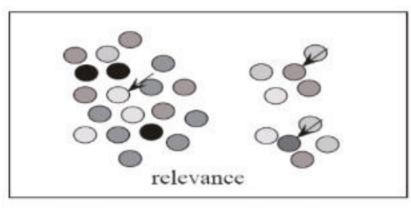
(a) a set of patterns



(b) redundancy-awar€ top-k

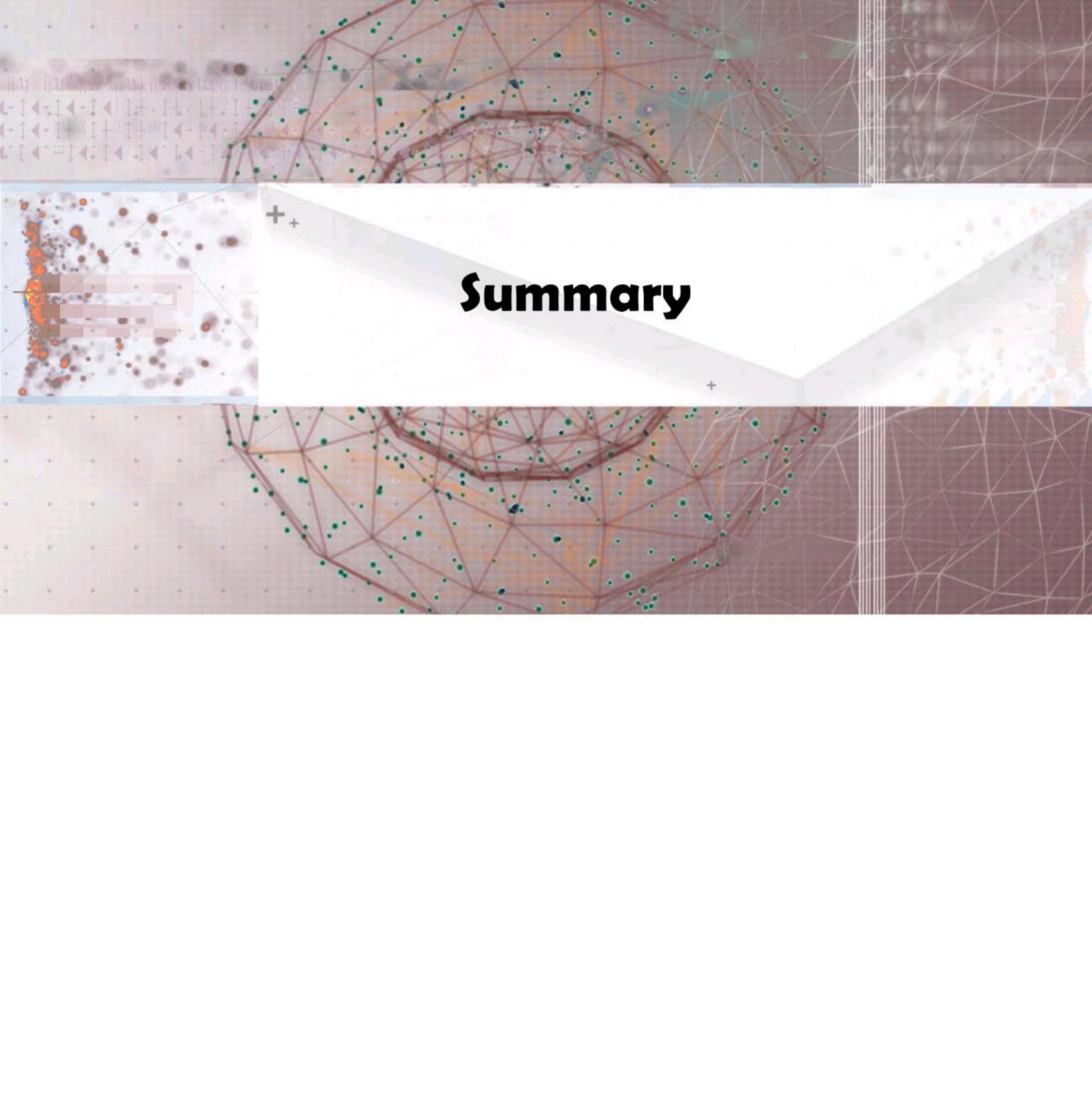


(c) traditional top-k



(d) summarization

- Method: Use MMS (Maximal Marginal Significance) for measuring the combined significance of a pattern set
- Xin et al., Extracting Redundancy-Aware Top-K Patterns, KDD'06



Summary: Mining Diverse Patterns

- Efficient methods have been developed for mining various kinds of patterns
 - Mining Multiple-Level Associations
 - Mining Multi-Dimensional Associations
 - Mining Quantitative Associations
 - Mining Negative Correlations
 - Mining Compressed and Redundancy-Aware Patterns

Recommended Readings

- R. Srikant and R. Agrawal, "Mining generalized association rules", VLDB'95
- Y. Aumann and Y. Lindell, "A Statistical Theory for Quantitative Association Rules", KDD'99
- K. Wang, Y. He, J. Han, "Pushing Support Constraints Into Association Rules Mining", IEEE Trans. Knowledge and Data Eng. 15(3): 642-658, 2003
- D. Xin, J. Han, X. Yan and H. Cheng, "On Compressing Frequent Patterns", Knowledge and Data Engineering, 60(1): 5-29, 2007
- D. Xin, H. Cheng, X. Yan, and J. Han, "Extracting Redundancy-Aware Top-K Patterns", KDD'06
- J. Han, H. Cheng, D. Xin, and X. Yan, "Frequent Pattern Mining: Current Status and Future Directions", Data Mining and Knowledge Discovery, 15(1): 55-86, 2007